### SUPPORTING INFORMATION

# Perovskite phase formation in pure and Sm- and La-substituted BiFeO<sub>3</sub> thin films under isothermal and non-isothermal regimes

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### Supplementary Note 1: Cross-section SEM images



Figure S1 - Cross-section SEM images of the bismuth ferrite-based thin films. Deviation calculated through the standard deviation based on 8 different measurements.



Supplementary Note 2: Time-dependent XRD data of samples treated at 600 °C

Figure S2 - X-ray diffraction data of pure BFO thin films thermal annealed at 600 °C for different times. P, F, and S are peaks related to perovskite, ferrite, and sillenite phases, respectively.



Supplementary Note 3: Structure and XRD profiles of analyzed phases

Figure S3 - Theoretical diffractograms, space groups, and idealized structures of the different compounds that can be formed during the synthesis of BFO-based materials. XRD profiles and structures were generated using VESTA.



### Supplementary Note 4: Atomic force microscopy measurements

Figure S4 - Atomic force microscopy images of the films submitted to the non-isothermal regime.

## **Supplementary Note 5: Summary of the tested theoretical models**

Group	Model	Symbol	$g(\alpha)$
Nucleation	Second-order power law	P2	$\alpha^{1/2}$
	Third-order power law	P3	$lpha^{1/3}$
	Fourth-order power law	P4	$lpha^{1/4}$
		A2	$[-\ln(1-\alpha)]^{1/2}$
	Avrami-Erofeyev	A3	$[-\ln(1-\alpha)]^{1/3}$
		A4	$[-\ln(1-\alpha)]^{1/4}$
Geometrical	Contracting area	R2	$1 - (1 - \alpha)^{1/2}$
contraction	Contracting volume	R3	$1 - (1 - \alpha)^{1/3}$
	1D diffusion	D1	$\alpha^2$
Diffusion	2D diffusion	D2	$[(1-\alpha)\ln(1-\alpha)] + \alpha$
	3D diffusion	D3	$[1 - (1 - \alpha)^{1/3}]^2$
	First-order	F1	$-\ln(1-\alpha)$
Reaction order	Second-order	F2	$[1/(1-\alpha)] - 1$
	Third-order	F3	$(1/2)[(1-\alpha)^{-2}-1]$

Table S1 - Integral functions of reaction kinetic models tested to fit the experimental data collected under non-isothermal conditions.

#### Supplementary Note 6: Fits of experimental data



Figure S5 - Experimental data converted to  $\ln[g(\alpha)/T^2]$  using each of the models shown in Table S1 and respective fits with the Coats-Redfern approximation.





Figure S6 - Pre-exponential constant and activation energies obtained with each kinetic model for the studied BFO-based thin films. Error bars are the fit residuals.